| Wight, Ingrid  | Issue Classification | Application/Control No.    | Applicant(s)/Pa WENG ET AL. | Applicant(s)/Patent under Reexamination<br>WENG ET AL. |
|--|----------------------|----------------------------|-----------------------------|--|
| ORIGINAL  SUBCLASS  CLAIMED  CROSS REFERENCE(S)  CROSS REFERENCE(S)  UBCLASS (ONE SUBCLASS PER BLOCK)  V. S/11/06  V. S/11/06  V. S/11/06  V. CORE CROSS REFERENCE(S)  CROSS REFERENCE(S)  CLAIMED  NON-CLA  S / 100  C   C   F   1 / 16  C   C   C   F   1 / 16  C   C   C   C   T / 16  C   C   C   C   C   C   C   C   C   C  |                      | Examiner<br>Wright, Ingrid | Art Unit 2835               |  |
| CROSS REFERENCE(S)  CROSS REFERENCE(S)  UBCLASS (ONE SUBCLASS PER BLOCK)   | ORIGINAL             |                            | INTERNATIONAL               | CLASSIFICATION   |
| CROSS REFERENCE(S)  CROSS REFERENCE(S)  CHOCLASS (ONE SUBCLASS PER BLOCK)  COA: Print Claims Allowed: 22  COA: Print Claim(s)  | CLASS                | SUBCLASS                   | CLAIMED                     | NON-CLAIMED  |
| CROSS REFERENCE(s)  UBCLASS (ONE SUBCLASS PER BLOCK)  V S/11/06  V S/11/06  COBB HEIRED ASOTORNOLL  (Date)  COBB HEIRED ASOTORNOLL  (Primary Examiner)  (Primary E |                      | <b>±</b> 0                 | X 7 7 5                     |  |
| V S/11/06 (Date)  V S/15.06  Chimary Examiner)  (Primary Examiner)  (Primary Examiner)  (Primary Examiner)  (Columnia (Primary | CROSS REFERENCE(\$   |                            | -                           |  |
| Solution (Date)  (Date)  (Primary Examiner)  (Date)  |                      | ASS PER BLOCK)             |                             |  |
| Solution (Primary Examiner) Chate)  (Date)  (Primary Examiner) Chief (Date)  (Primary Examiner) Chief (Date)  (Primary Examiner) Chief (Date)  (Primary Examiner) Chief (Date)   |                      |                            |                             |  |
| (Date) (Date) (Org. Edited ASCIONAL AND CONTROL (Date) (Da |                      | 1/4                        | Total Cl                    |  |
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